



#62877

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Michael Weber-Grabau et al. PATENT APPLICATION

Serial No.: 09/927,102

Group Art Unit: 2877

Filed: August 10, 2001

Examiner:

For: OPTICAL CRITICAL DIMENSION METROLOGY SYSTEM

INTEGRATED INTO SEMICONDUCTOR WAFER PROCESS TOOL

Information Disclosure Statement

Hon. Assistant Commissioner

for Patents

Washington, D.C. 20231

Sir:

The following information is submitted in compliance with Applicants' duty of disclosure under 37 CFR § 1.56. A copy of each reference is enclosed.

U.S. Patents

| <u>Pat. No.</u> | <u>Patentee</u> | <u>Grant Date</u> |
|-----------------|----------------------|-------------------|
| 5,067,805 | Corle et al. | 11/26/91 |
| 5,486,701 | Norton et al. | 01/23/96 |
| 5,517,312 | Finarov | 05/14/96 |
| 5,604,344 | Finarov | 02/18/97 |
| 5,608,526 | Piwonka-Corle et al. | 03/04/97 |
| 5,682,242 | Eylon | 10/28/97 |
| 5,747,813 | Norton et al. | 05/05/98 |
| 5,859,424 | Norton et al. | 01/12/99 |
| 5,885,045 | Rush | 03/23/99 |
| 5,889,593 | Bareket | 03/30/99 |
| 5,943,122 | Holmes | 08/24/99 |
| 5,957,749 | Finarov | 09/28/99 |
| 5,991,022 | Buermann et al. | 04/27/99 |

Foreign Patent Document

| <u>Doc. No.</u> | <u>Country</u> | <u>Publ. Date</u> |
|-----------------|----------------|-------------------|
| EP 0973068 A2 | EPO | 01/19/2000 |
| EP 0973069 A2 | EPO | 02/19/2000 |

Other Reference

Nanometrics News Release, "Applied Materials/Nanometrics Sign Pact For Metrology Integration", Copyright 1998 Worldwide Videotex, Electro Manufacturing, November 1998, No. 11, Vol. 11.

CERTIFICATE OF MAILING

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to: Asst. Commissioner for Patents, Washington, D.C. 20231

Signed: *Sally Azevedo*
Typed Name: Sally Azevedo

Date: October 29, 2001

Respectfully submitted,

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| FORM PTO-1449 | Atty. Docket No. SEN-002 | Serial No. 09/927,102 |
| LIST OF PRIOR ART CITED BY APPLICANT | Applicant: Michael Weber-Grabau et al. | |
| | Filing Date: August 10, 2001 | Group: 2877 |

U.S. PATENT DOCUMENTS

| Examiner Initial* | Document Number | Grant Date | Name | Class | Sub Class | Filing Date |
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| AA | 5,067,805 | 11/26/91 | Corle et al. | 359 | 235 | |
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| AD | 5,608,526 | 03/04/97 | Piwonka-Corle et al. | 356 | 369 | |
| AE | 5,682,242 | 10/28/97 | Eylon | 356 | 401 | |
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| AK | EP0973068 | | EPO | | | X |
| AL | EP0973069 | | EPO | | | X |

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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| AM | Nanometrics News Release, "Applied Materials/Nanometrics Sign Pact For Metrology Integration", Copyright 1998 Worldwide Videotex, Electro Manufacturing, Nov. 1998, No. 11, Vol. 11. |
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| EXAMINER: | DATE CONSIDERED: |
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*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



FORM PTO-1449

Atty. Docket No.
SEN-002Serial No.
09/927,102LIST OF PRIOR ART
CITED BY APPLICANTApplicant:
Michael Weber-Grabau et al.Filing Date:
August 10, 2001Group:
2877

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| BB | 5,991,022 | 04/27/99 | Buermann et al. | 356 | 319 | |
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